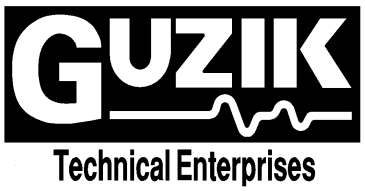



# Release Notes

# WITE32

# (web-site version)

**Version 2.60**

**02/14/2001**

**Guzik Technical Enterprises**

# TABLE OF CONTENTS


**Chapter 1 Introduction** 3

**Chapter 2 New Features Introduced in WITE32** 4

2.1 RWA-2585B 1G Tester Support 4
2.2 Digital Measurements 5
2.3 Guzik Digital PRML Channel Improvements 5
2.3.1 Low-Frequency High-Pass Filter 5
2.3.2 New Shorter Preambles 5
2.3.3 Improved Algorithm of Reshaping Procedure 5
2.3.4 Shape Defect Compensation 5
2.3.5 Improved Digital Clock Recovery Algorithm 5
2.3.6 Digital Clock Recovery Time Constants Control 5
2.3.7 Optimization of Digital Clock Recovery Time Constants and SDC Optimization 5
2.3.8 Minimum Data Rate Limitation Reduced 6
2.4 Servo Improvements 6
2.4.1 User-Defined Servo Range 6
2.4.2 Modifications In The Servo Calibration Dialogue Box 6
2.5 User Interface Modifications 6
2.5.1 Test Options And Measurement Options Dialogue Boxes 6
2.5.2 RWA Control Parameters In The Control Menu 6
2.5.3 Error Tests Became a Separate External Module 6
2.6 PRML Chip Channel 7
2.7 Head Amplifiers 7
2.8 Spinstands 7
2.9 Guzik Graph Modifications 8
2.9.1 Fixed Zoom Option In Guzik Graph 8
2.9.2 Nested Zooms 8
2.9.3 Truncated Plots 9
2.10 Spectral Integral SNR Test 10
2.11 Pulse Profile Test 10
2.12 Windows 2000 support 10
2.13 Miscellaneous 11

**Chapter 3 Fixed Bugs** 12

3.1 Spinstands 12
3.2 Digital Measurements 12
3.3 PRML Chips 13
3.4 Miscellaneous 13

**Chapter 4 Known Problems And Solutions** 16

# CHAPTER 1

# INTRODUCTION

The 2.60 release incorporates new features introduced after the WITE32 2.54 release. (This document uses the WITE32 2.54 release notes as a base line for comparison.)

# CHAPTER 2
# NEW FEATURES INTRODUCED IN WITE32

## 2.1 RWA-2585B 1G Tester Support

A new revision of RWA-2585 tester is introduced in January 2001. This revision is called RWA-2585B 1G. The difference between RWA-2585B 1G and older testers is a new revision of PRML Chip Adapter Interface motherboard.

| | RWA-2585A 1G | RWA-2585B 1G |
|---|---|---|
| Chip Adapter Interface Board Name | CAI | PCA-2000 |
| Chip Adapter Interface Board Part Number | 306260 | 311680 |
| Part Number of the Parallel Data cable between RWA and ANA box | 460597 | Not required |

Note: RWA-2585B 1G does not require a Parallel Data cable between RWA and ANA box.

### Backward Compatibility

The functionality of older CAI board is fully implemented and supported by PCA-2000. There are no differences between PCA-2000 and CAI boards from the WITE32 software User Interface point of view.

### New Features

The new PCA-2000 Chip Adapter Interface board provides PRML Measurements with data rates up to 2 Gbit/s (limited by PRML chip installed). New PCA-2000 Chip Adapter Interface board can also operate in Stand Alone mode. Please log on to www.guzik.com for more details on PCA-2000 features.

### PRML Chip Drivers Version

To work with WITE32 ver. 2.60 using a new chip adapter interface, you need to install an updated PRML Chip driver ver.2.60. The following updated drivers are provided on the WITE32 installation CD:

- Venom,
- M16 / M16+ / Coral,
- SSI4937A.

If you are using PRML chip other than listed above, you need to request PRML chip drivers ver. 2.60 from Guzik Technical Customer Support.

## 2.2 Digital Measurements

The new Digital Measurement features in WITE32 ver.2.60 are:

- All-digital parametric mode
- Digital Filter

Note: Please order your copy of WITE32 ver.2.60 to get the detailed description of these features.

## 2.3 Guzik Digital PRML Channel Improvements

### 2.3.1 Low-Frequency High-Pass Filter

The low-frequency high-pass filter is implemented to provide low frequency noise filtering. This addition significantly improves the performance of the clock recovery on the signals with excessive low-frequency noise.

Note: Please order your copy of WITE32 ver.2.60 to get the detailed description of this feature.

### 2.3.2 New Shorter Preambles

The method of calculation of the length of the preambles in the patterns for Guzik digital PRML channel has been changed in order to reduce the length of the preambles for relatively low system frequencies.

Note: Please order your copy of WITE32 ver.2.60 to get the detailed description of this feature.

### 2.3.3 Improved Algorithm of Reshaping Procedure

The algorithm of the reshaping procedure of the Guzik channel optimization test has been improved to increase robustness and reliability.

Note: Please order your copy of WITE32 ver.2.60 to get the detailed description of this feature.

### 2.3.4 Shape Defect Compensation

Shape defect compensation feature provides the compensation of the non-ideal PRML shape of an equalized signal, like amplitude asymmetry, shift of the baseline, etc.

Note: Please order your copy of WITE32 ver.2.60 to get the detailed description of this feature.

### 2.3.5 Improved Digital Clock Recovery Algorithm

The algorithm of the digital clock recovery has been improved to provide better lock on poor signals. This modification significantly improves the ability to lock to the signal after initial reshaping stage of the Guzik channel optimization procedure, thus increasing the working range of optimization procedure.

Note: Please order your copy of WITE32 ver.2.60 to get the detailed description of this feature.

### 2.3.6 Digital Clock Recovery Time Constants Control

To provide more flexibility with the digital clock recovery setup, the control of the time constant of all internal digital clock recovery loops is now available in the Digital Measurements configuration box.

Note: Please order your copy of WITE32 ver.2.60 to get the detailed description of this feature.

### 2.3.7 Optimization of Digital Clock Recovery Time Constants and SDC Optimization

Two new steps were added to the Guzik PRML channel optimization procedure:

- The optimization of the digital clock recovery time constants

- The optimization of the parameters of SDC module

Note: Please order your copy of WITE32 ver.2.60 to get the detailed description of this feature.

### 2.3.8 Minimum Data Rate Limitation Reduced

The minimum data rate limitation for Guzik Digital PRML channel (available in RWA-2585A testers and later) was reduced from 62.5 MBit/s to 20 MBit/s.

Note: Please order your copy of WITE32 ver.2.60 to get the detailed description of this feature.

## *2.4 Servo Improvements*

### 2.4.1 User-Defined Servo Range

Starting from WITE32 ver. 2.60, the Servo Range is user configurable. You can specify any range you want in the Write Servo Configure dialogue box.

Note: Please order your copy of WITE32 ver.2.60 to get the detailed description of this feature.

### 2.4.2 Modifications In The Servo Calibration Dialogue Box

The servo calibration procedure and configuration settings were changed to support user-defined servo range and improve servo attenuator calibration.

Note: Please order your copy of WITE32 ver.2.60 to get the detailed description of this modification.

## *2.5 User Interface Modifications*

### 2.5.1 Test Options And Measurement Options Dialogue Boxes

The C*onfigure* | *Test Options* dialogue box has been split into two dialogue boxes: C*onfigure* | *Test options* and *Configure* | *Measurement Options*.

Note: Please order your copy of WITE32 ver.2.60 to get the detailed description of this modification.

### 2.5.2 RWA Control Parameters In The Control Menu

The RWA control parameters in the Control menu were re-grouped.

Note: Please order your copy of WITE32 ver.2.60 to get the detailed description of this modification.

### 2.5.3 Error Tests Became a Separate External Module

The Bitshift (Error Rate), Comparatror, and Popcorn tests, which are known as the *Error tests*, have been split from the WITE.EXE application to the separate external module.

Note: Please order your copy of WITE32 ver.2.60 to get the detailed description of this modification.

## 2.6 PRML Chip Channel

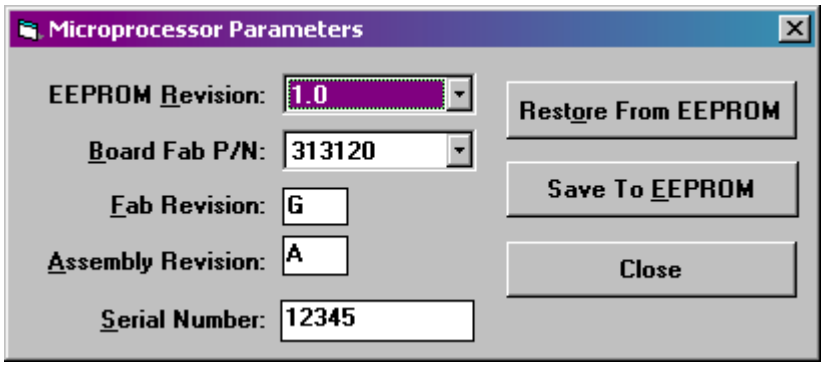
1. The *Abort* button was added to the procedure of chip optimization to cancel a lengthy execution. This modification was done for M16+ PRML chip only.
2. The range setting of Read Bias optimization in the PRML Chip optimization dialogue box was reduced by 0.2 mA.
3. The *Print* menu item was added in the window for printing a difference between two sets settings of the chip registers.
4. The PRML Chip optimization procedure for M16+ chip now reports QM and QM_reg values = –1 in case of optimization failure. You can set up the Grading system to detect PRML chip optimization failures.

## 2.7 Head Amplifiers

1. The following head amplifiers are initially supported in WITE32 ver. 2.60:
    - VM6214 chip on PADDLE board
    - ThorOrca chip Rev.3 on Thor VTC-3 board
2. The following head stacks are initially supported in WITE32 ver. 2.60:
    - 81G5014 chip – PUMA
    - VM5840 chip – CENTURION2
    - Mercury chip – RIGEL_2
3. The properties of SR1766 and VM5410D3 based head stacks are modified to make them similar to the Mercury head stack.

## 2.8 Spinstands

1. The *Parameters* | *Microprocessor Parameters* menu item has been added to main menu of the Spinstand Alignment Program (WDCP). This menu item is available in the Factory Setting Mode for S-1701A+ spinstands. The *Parameters* | *Microprocessor Parameters* dialogue box layout is shown on the picture below:




2. The default values of the following Spinstand driver parameters have changed:
    - The Outer Limit Radius – 1.87 µInch
    - The Home Radius – 2.3 µInch

These values are applied to all newly created products. If you already had a product, created in previous version of WITE32, the values of these parameters will remain unchanged.

3. Non-implemented *Help* | *Contents* and *Help* | *Technical Support* menu items have been removed from the Spinstand Alignment Program (WDCP).

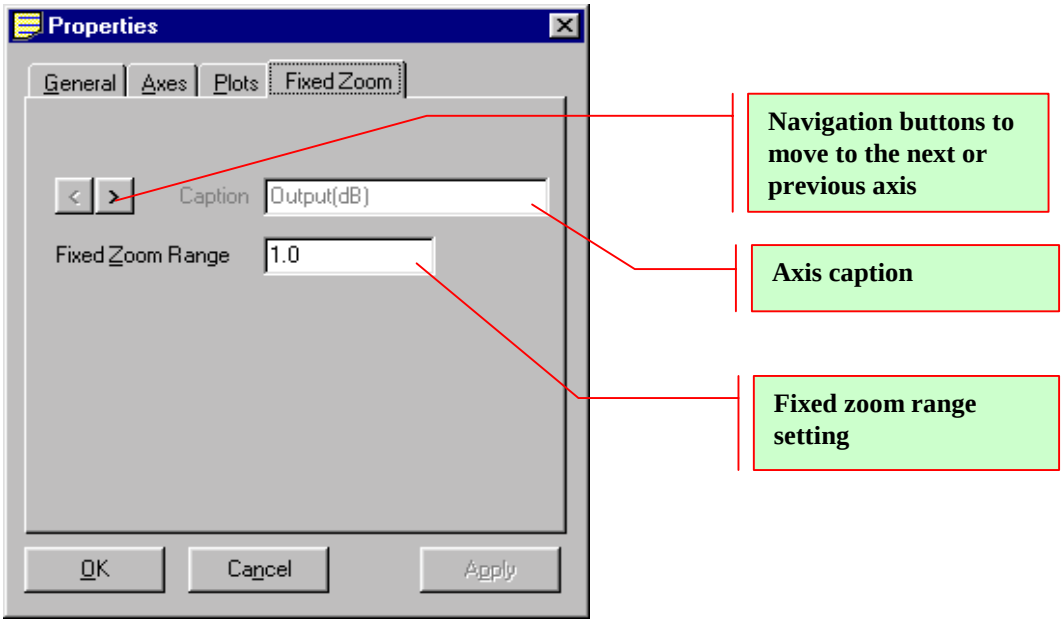
4. If the spinstand *Home Radius* setting exceeds the *Reset Radius* setting, the Spinstand Alignment Program (WDCP) automatically adjusts the *Home Radius* value to be smaller than the *Reset Radius* value. Both values are available in the *Set Product Parameters* dialogue box of the Spinstand Alignment Program.

## 2.9 Guzik Graph Modifications

### 2.9.1 Fixed Zoom Option In Guzik Graph

The fixed zoom option allows magnifying the chosen area in accordance with the fixed range values for axis, which you can define in the Guzik Graph preferences.

To invoke the fixed zoom capability, you move the mouse cursor to the desired point in the graph window, press and hold the <Ctrl> key on your keyboard, and then double click on the right mouse button. The graph will change axis scales of the chosen region according to the fixed zoom settings. The center of the area will be determined by the mouse pointer, and the region size will be determined by the corresponding *Fixed Zoom Range* for each axis. The fixed zoom range settings can be changed in the *Fixed Zoom* tab of the Guzik graph *Properties* dialogue box, please see the picture below. To open the Guzik graph *Properties* dialogue box, please click on the *Options* | *Preferences* menu item of the pull-down menu in the graph window.



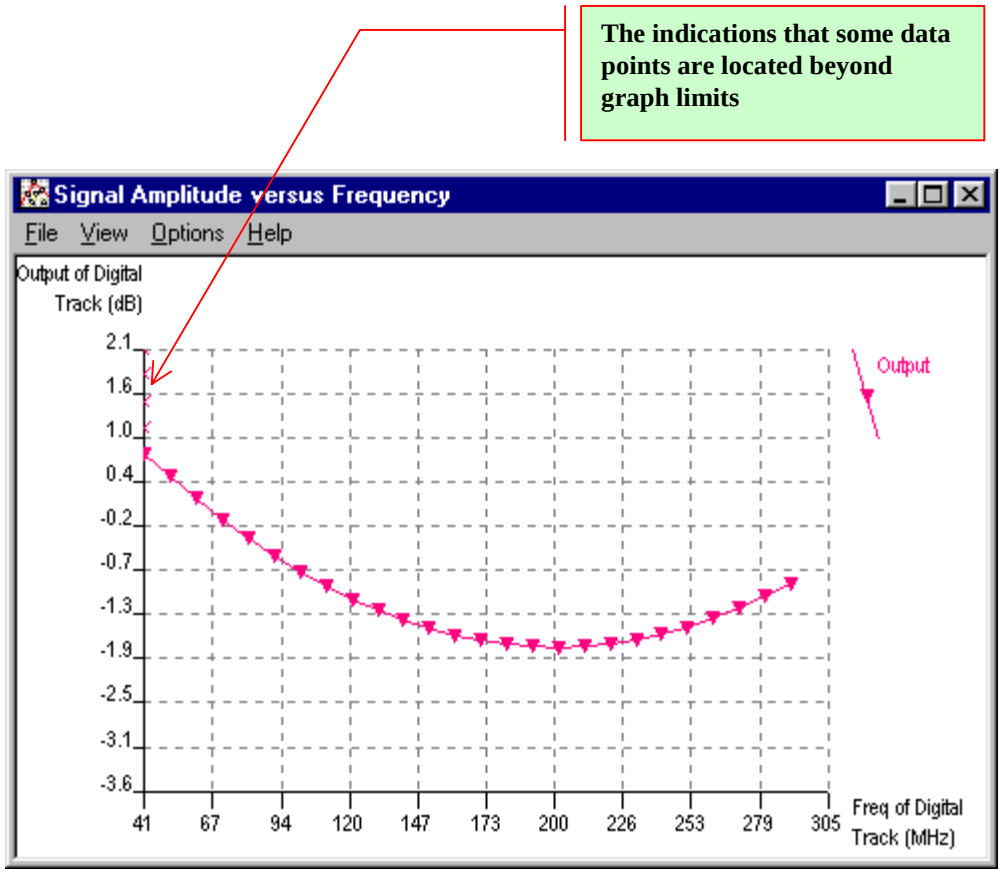

### 2.9.2 Nested Zooms

Starting from WITE32 ver.2.60, you can perform nested zoom operations. This capability allows magnifying the chosen area to the desired level step by step. To start zooming, press and hold the <Ctrl> key on the keyboard, then press and hold the left mouse button. While holding the left mouse button and the <Ctrl> key start to drag the mouse to select desired graph region. Release the left mouse button, and

then the <Ctrl> key to complete the zoom operation. Repeat the above procedure as necessary to zoom further. You can make up to three nested zooms. Press the <Esc> key on the keyboard to undo zooming.

### 2.9.3 Truncated Plots

If you have fixed axis scale settings and some points of the plot fall out of the visible area, the Guzik Graph will display V-shaped marks on the boundaries of the plot.



## 2.10 Spectral Integral SNR Test

An extended version of the Spectral SNR test has been introduced in the Parametric Tests module.

The new test name is Spectral Integral Signal-to-Noise Ratio Test (SpiSNR) and has the following improvements over the standard Spectral SNR test.

- The test can write a different frequency prior to measuring RMS of noise.
- The RMS of noise (without DC-erase) has configurable skip range.
- The test measures background noise by means of lifting the head or cutting Bias current off (if Bias cutoff feature supported by the head amplifier)
- The test outputs not only SNR but also the RMS of both signal and the noise.
- The test can make a sweep of SNR over a range of frequencies, in other words it can build a plot of SNR vs. written signal frequency.
- The test can work with Guzik Spectrum Analyzer or with an external one connected through GPIB interface.

Note: Please order your copy of WITE32 ver.2.60 to get the detailed description of this test.

## 2.11 Pulse Profile Test

1. The Pulse Profile test for RWA-2585 tester now runs in Asynchronous mode. Pulse Profile test modes are described in WITE32 ver. 2.51 Release Notes. The following modes are supported in WITE32 ver.2.60:
   - Synchronous pulse profile (available in RWA-1632 family of testers),
   - Asynchronous pulse profile (available in RWA-2585 family of testers).
2. The Pulse profile test now arranges peaks "to scale", if the *Pulse Polarity* mode is set to *Both*. When *Both* polarity is selected for the Pulse Profile test, the negative pulse is displayed shifted to the right from the positive pulse. This shift reflects the real distance between positive and negative pulses in the pulses and may be used to observe the timing asymmetry of the signal. Note that if the X-axis limits are fixed for Pulse Profile test in your setup, you may not see the negative pulse as it may be out of the screen.
3. Bandwidth limitation for synchronous pulse profile mode (RWA-1632 tester) was increased to 550 MHz.
4. *Pulse Profile* test configuration settings

   As it was mentioned above, the Pulse Profile test for RWA-2585 family of testers runs in asynchronous mode. In this mode the delay range settings the *Delay Range* frame are fixed
   - *From* is always set to 0
   - *To* is always set to 32

## 2.12 Windows 2000 support

WITE32 ver. 2.60 can run under Windows 2000 operating system. Operation of WITE and its components is the same as under Windows 95/98 with the following restrictions:

- PCI Guzik host adapter is required with Windows 2000. Older ISA Guzik host adapter cannot be used with Windows 2000. However WITE 2.60 running under Windows 95/98 can use ISA Guzik host adapter.

- Installation of WITE and Guzik PCI boards (PCI Host adapter and Beetle) under Windows 2000 requires Administrator privileges.
- Operation of WITE itself after installation does not require any special privileges.

The supported operating systems are:

- Windows 95
- Windows 95 OSR2
- Windows 98
- Windows 2000

We did not approve, and do not guarantee WITE32 compatibility with other Operating Systems, such as Windows NT 4.0 or Windows ME.

## 2.13 Miscellaneous

1. The *Errors at the test end* option was added to the *Production* frame of the *Configure* | *Test Options* dialogue box. When this option is checked, all RWA errors messages and warning messages occurred during production test will be displayed at the end of the production test in one message box.
2. New parameter TPWrRdWidth = TPWrWidth + TPRdWidth was added to the Track Profile Test output.
3. Modification in printed output: In the older versions, no data will be printed if a print section only contains some system information (zone name, setup name, track number, head number, test name, statistic type and head serial number). For example, if a print section only contains zone name, setup name, track number and head number, a header for these four items is printed but their actual data is not. Starting from this version, the data is always printed.
4. The *Read* operation invoked from the WITE Dashboard now performs main gain adjustment.

# CHAPTER 3
# FIXED BUGS

The following bugs were discovered in WITE32 ver.2.54 or earlier, and fixed in WITE32 ver.2.60. The description below explains the bug behavior as it appeared in WITE32 ver.2.54.

## 3.1 Spinstands

1. Spinstand Alignment program can lose connection with Optical Alignment software in case more then one installation of WITE32 exists on the same computer.
2. Spinstand Alignment program can lose connection with Balancing software in case more then one installation of WITE32 exists on the same computer.
3. If a head loader is unlocked during start of Spinstand, the servo compatible spinstand can report itself as non-servo spinstand.
4. When *Balancing* test is started from the Operator Panel, the error message *"Device is not SELECTED"* appears.
5. If the Crash Protector Emergency situation happens for the spinstand with the Microprocessor Board P/N 313120, the error message does not disappear until you reset the spinstand by the red button or by the power switch.
6. The wrong error message "*[MSTPDSP]: For X-Positioner device unknown error condition*" appears for the spinstands with Guzik GTEMR4UM head amplifiers P/N 311890 and 313210.
7. If the Spinstand has a safety Cover and the Cover is opened, every Start Device or Reset command from Device Alignment Program causes spinstand to perform a reset operation.
8. The original Mouse Pointer is not restored after some long operations in Device Alignment Program.
9. The *"1701CF/A Error: 4005, SPN: Timeout in receiving Data"* message pops up intermittently for S-1701CF or S-1701A spinstand during the track table recalculation.

## 3.2 Digital Measurements

1. The *Optimal* acquisition time selection in the *Control* | *Digital Measurements* dialogue box works incorrectly with PRML Chip patterns.
2. The *Run* button in Signal Display window for 1632 testers is enabled, but generates an error message.
3. The read-only combo boxes *Write option*, *Pattern*, *Direction*, and *Mode* in Digital Parametric test configuration form allow text editing.
4. Redundant message *"Step greater than … nS will not yield good interpolation"* appears when closing the Pulse Profile test configuration form even though the Step value cannot be edited for Asynchronous mode (RWA-2585).
5. Profile step setting generated by the *Optimal Step* button in the Pulse Profile test configuration form in synchronous mode (RWA-1632) may cause an incorrect *"Step greater than … nS will not yield good interpolation"* message.
6. If the *Both* setting of triggering pulse is selected for Pulse Profile test in synchronous mode (RWA-1632), and only the first pulse after the triggering pulse is included in the profile, the TAA and PW values are calculated incorrectly.

7. In the *Control* | *Digital Measurements* dialogue box, the default value of the *Custom* acquisition time is 0. An attempt to select the Custom acquisition time radio button causes the error message *"0 < Acquisition Time <= 2000"*.

## 3.3 PRML Chips

1. Sometimes (for example, when calibration is not done) PRML chip is not initialized properly. In this case you can see strange chip behavior in different ways. For example, it is possible that there is no write data at the output of chip, or chip optimization does not work. Since this bug fixed in each individual PRML chip driver, we strongly recommend updating your PRML chip drivers to ver.2.60. The following updated drivers are provided on the WITE32 installation CD: Venom, M16 / M16+ / Coral, SSI4937A. If you are using other PRML Chip drivers, please request an updated driver ver.2.60 from Guzik Customer Support.
2. A problem with Read Bias Optimization in the PRML Chip Optimization. Optimization fails when you start the optimization procedure with enabled checkbox for read bias optimization, before running the initial setup procedure.
3. The *"Automation Error"* message pops up when you press the *Abort Sweep* button in the PRML Chip configuration dialogue box.
4. If you plug M16+ PRML Chip adapter revision "A", "B", or "C" in the RWA-1601/1632 tester, WITE32 does not give any error message. These revisions are not compatible with RWA-1632, and starting from WITE32 ver.2.60 you will get an error message.

   Note: You must have M16+ rev. "D" and above to be able to work with RWA-1601/1632 family of testers.

## 3.4 Miscellaneous

1. The bug fixed in the PCI host adapter driver. This bug manifests itself as an intermittent error message *"RWA power was interrupted"*.
2. After you remove an IPC-based external module from WITE32 (modules with EXE extension), running any test inside WITE32 will crash WITE32.
3. Modification in PWN Stability Test produces wrong results if the read current setting is enabled.

   Note: The PWN Stability Test time in WITE32 ver.2.60 will be longer comparing to previous versions, when the read current option is enabled.

4. The engineering dashboard does not switch to the disabled state when the *Calibrate All* procedure is running.
5. If you run the Production test from the Operator Panel, press the *Abort* button when the *Serial Numbers* dialogue is opened, then the aborted Production test does not stop after you press *OK* or *Cancel* in the *Serial Numbers* dialogue box.
6. If the *Test Counter* setting in the Engineering Mode dashboard is set to *Loop* (infinite test execution), the *"Overflow"* error message eventually pops up during test execution.
7. If you enable the Use Fast Offset option in the Track Profile test, select Overwrite filter, and specify more than one iteration, the Track Profile test produces incorrect results.
8. In the *Saturation* test setup dialogue box some controls do not have zone/setup editing capability.
9. In the *Spectrum Analyzer* test setup form some controls do not have zone/setup editing capability.
10. In the *Sector Amplitude Stability* test setup form some controls do not have zone/setup editing capability.

11. The *Track Profile* test setup form provides incorrect information about the F3 performance filter, if this filter is selected in the test setup.
12. If you run the EPROM Viewer utility while WITE32 is running, WITE32 crashes and EPROM Viewer shows incomplete data. WITE32 ver.2.60 does not allow starting EPROM Viewer utility while WITE32 is running.
13. The Negative Erase operation may not work properly until you open the *Control* | *Gate and Track Format* dialogue box and press the *Save* button.
14. During execution of the Auto Equalization calibration, the WCONTROL module disconnects if the CHOPPRF calibration pattern is not loaded (i.e. when CLKREC.EP2 pattern file is not selected in the *Configure* | *System* dialogue box). This bug can appear if in newly created product you open the *Calibration* | *Auto Equ* menu, immediately close it, and press the *Yes* button in the *"Save changes…"* message. Opening the *Auto Equ* form again produces the *"Invalid use of NULL"* message. If after that you press the *Restore* button, then the *"Run time error 94"* occurs, which disconnects the WCONTROL module.
15. In the *Control* | *Clock* menu of the *Engineering dashboard* main menu the unusual error message window pops up after several quick presses on the "Tab" key. The title of this message is "*WCONTROL message"*, the text of this message is one letter "*1*".
16. After running the comparator error test with the *Error Log* option enabled, the error results dialogue with the list of errors appears. If this list is empty (no errors were detected) and you try to double-click any item in this list, WITE32 crashes.
17. The *Export Result* window is not closed when user clicks the *Close WITE Window* button in the WITE32 Engineering mode dashboard.
18. In the Popcorn test setup menu, multiple error messages pop up if one of the following parameters is out of bound: *Write Length*, *Delay Before Read*, and/or *Read Length*. Starting from WITE32 ver.2.60 only one message pops up.
19. In the Popcorn test setup menu, the track format configuration gives incorrect information when the system is either in soft sector mode or hard sector mode.
20. If you click the *Abort* button while the system is running the production test in _ZOutside zone, only the tests in _ZOutside zone are aborted, tests in the other zones are still executed.
21. If the Production test is configured to run tests in _ZOutside zone, and you click the *Cancel* button in the *Serial Number* dialogue box, the next production run will not execute tests in _ZOutside zone. After that no results from _ZOutside zone tests are reported.
22. If Normalization coefficient table is empty, and you click on the first row of the empty table, the *"Subscript out of range"* error message pops up.
23. If you remove any of the following external modules from WITE: Parametric Tests, Composite Tests, Error Tests and Digital Tests, and adds some new zones/setups to WITE, no new zone/setup records will be created for these test modules when they are selected into WITE again.
24. While the *Grading Limit* dialogue box is opened, adding/deleting grades or changing grade priority without committing (i.e. saving) the changes may mess up the internal grading system definition table. Different kinds of errors will pop up, for example, "Duplicated grade name", "Some grades are missing from the selection list", etc. Starting from WITE32 ver.2.60, the *Grading Limit* dialogue box is opened as modal window. Moreover, you must commit any changes before you are allowed to open the limit menu.
25. If the ASCII filename is changed in WResult configuration menu, and the *Fast Output* option is enabled, the new filename is not used until WITE32 is terminated and restarted again.

26. If the grading result form and failure result form are minimized when WITE is terminated, the *"Invaild procedure call"* error message pops up.
27. If the *Station ID* field in the *Configure* | *Identification* | *Station ID* window contains the string in a format "RWAxxxxx_SSyyyyy", the WITE32 software does not update “xxxxx” with the RWA Serial Number, and “yyyyy” with the Spinstand Serial Number.
28. Popcorn test: incorrect TAA measurement during threshold calculation. If the Popcorn criterion is set to percent from the TAA of a specified pattern with a non-empty preamble, the TAA measurement opens the read gate at the beginning of the preamble (must be at the end of the preamble). The problem can be observed in all 32-bit WITE releases. Starting from WITE32 ver. 2.60, no preamble is written for the pattern used for threshold calculation.
29. An intermittent *"Invalid procedure call"* message during external module installation. The problem can be observed in all WITE32 releases.
30. If any configuration dialogue box from the *Control* pull-down menu of WITE32 Engineering mode dashboard is opened, and currently selected zone is not the first zone in the list of zones in the *Configure* | *Zones* window, the data in the configuration dialogue box becomes inconsistent with the database after you press the *Restart* button in the WITE32 Engineering mode dashboard. The problem can be observed in all WITE32 releases.
31. The configuration forms for *Parametric Tests* module occasionally do not reload data, if current Zone/Setup has changed. The problem can be observed in all WITE32 releases.
32. The *Calibrale All* operation does not work properly if RWA does not have VFO board installed. An error message *"Can not find test Calib Bitshift"* appears in some cases.
33. Error messages *"Invalid procedure call or argument”* and *"No current record”* pop up after trying to start the *Calib Auto Equ* test, if product was created in old revision of WITE.
34. The *Abort* button does not disappear after canceling *Calibrate All* operation.
35. The graphic result windows (plots) generated by tests from the Parametric Tests group are not closed after pressing the *Close WITE windows* button on the WITE32 Dashboard.
36. In the *Configure* | *Soft Button* dialogue box, assigning a *"(none)"* choice to soft button doesn’t clear previous assignment.
37. The *Control* | *Gate and Track Format* configuration dialogue: the Read Gate and Write Gate limits are not updated on system pattern change.
38. Popcorn Test: The *Load Head* option is enabled even if spinstand does not support this capability.
39. Spectral Integral SNR Test: The *Spinstand load/unload parameters* option is enabled even if the device driver does not support this capability.
40. Guzik Graph: Clicking on the *Print* button can cause WITE32 crash if printer is absent.
41. The *Output to DB* option located in the *NLTS versus Write Current* test configuration dialogue box does not produce output results to database in accordance with the specification.

# CHAPTER 4
# KNOWN PROBLEMS AND SOLUTIONS

The following issue was reported for the ASCII results export in WITE32. If you click the following sequence to save the test results to an ASCII file, you will not get the filename extension you expected:

Click the *Export!* menu item in a text result window, the *Export Result* window appears

Click the *Export* button in the *Export Result* window, the *Save As* window appears

Type in the file name: RESULT.RWA

Save as type: Log Files (*.WEX)

The generated file name will be RESULT.RWA.WEX

In fact, this is a standard feature of Microsoft Windows File Dialog box. If the default file extension is not null, the default extension is always appended at the end of the filename (no matter the filename has an extension or not). To bypass the automatic appending of default extension, user can select the "All Files" extension (*.*). There is no way to tell Windows not to append the default extension when it is not null.